TOSHIBA Field Effect Transistor Silicon P Channel MOS Type (L<sup>2</sup>-π-MOSV)

## 2SJ380

# Relay Drive, DC-DC Converter and Motor Drive Applications

• 4-V gate drive

• Low drain-source ON resistance: RDS (ON) =  $0.15 \Omega$  (typ.)

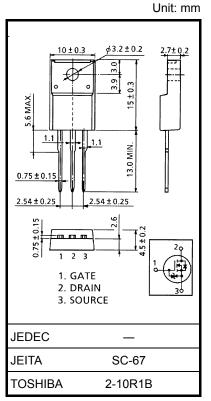
• High forward transfer admittance:  $|Y_{fs}| = 7.7 \text{ S (typ.)}$ 

• Low leakage current:  $IDSS = -100 \mu A (max) (VDS = -100 V)$ 

• Enhancement mode:  $V_{th} = -0.8 \sim -2.0 \text{ V (V}_{DS} = -10 \text{ V}, I_D = -1 \text{ mA)}$ 

#### **Absolute Maximum Ratings (Ta = 25°C)**

Characteristics		Symbol	Rating	Unit	
Drain-source voltage		$V_{DSS}$	-100	V	
Drain-gate voltage ( $R_{GS} = 20 \text{ k}\Omega$ )		$V_{DGR}$	-100	V	
Gate-source voltage		V <sub>GSS</sub>	±20	V	
Drain current	DC (Note 1)	I <sub>D</sub>	-12	А	
	Pulse (Note 1)	I <sub>DP</sub>	-48		
Drain power dissipation	n (Tc = 25°C)	P <sub>D</sub>	35	W	
Single pulse avalanche energy (Note 2)		E <sub>AS</sub>	312	mJ	
Avalanche current		I <sub>AR</sub>	-12	Α	
Repetitive avalanche energy (Note 3)		E <sub>AR</sub>	3.5	mJ	
Channel temperature		T <sub>ch</sub>	150	°C	
Storage temperature range		T <sub>stg</sub>	-55~150	°C	



Weight: 1.9 g (typ.)

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

#### **Thermal Characteristics**

Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	R <sub>th (ch-c)</sub>	3.57	°C/W
Thermal resistance, channel to ambient	R <sub>th (ch-a)</sub>	62.5	°C/W

Note1: Ensure that the channel temperature does not exceed 150°C.

Note 2:  $V_{DD} = -25~V$ ,  $T_{ch} = 25^{\circ}C$  (initial), L = 2.94~mH,  $R_G = 25~\Omega$ ,  $I_{AR} = -12~A$ 

Note 3: Repetitive rating: pulse width limited by maximum junction temperature

This transistor is an electrostatic-sensitive device. Please handle with caution.



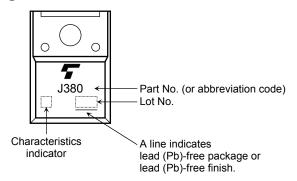
## **Electrical Characteristics (Tc = 25°C)**

Chara	acteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cur	rent	I <sub>GSS</sub>	$V_{GS} = \pm 16 \text{ V}, V_{DS} = 0 \text{ V}$	_	_	±10	μА
Drain cut-off curre	ent	I <sub>DSS</sub>	$V_{DS} = -100 \text{ V}, V_{GS} = 0 \text{ V}$	_	_	-100	μА
Drain-source brea	akdown voltage	V (BR) DSS	$I_D = -10$ mA, $V_{GS} = 0$ V	-100	_	_	V
Gate threshold vo	oltage	V <sub>th</sub>	$V_{DS} = -10 \text{ V}, I_D = -1 \text{ mA}$	-0.8	_	-2.0	V
Drain-source ON	resistance	Ppo (ON)	$V_{GS} = -4 \text{ V}, I_D = -6 \text{ A}$		0.25	0.32	Ω
Drain-source ON resistance		R <sub>DS</sub> (ON)	$V_{GS} = -10 \text{ V}, I_D = -6 \text{ A}$	_	0.15	0.21	2.2
Forward transfer	admittance	Y <sub>fs</sub>	$V_{DS} = -10 \text{ V}, I_D = -6 \text{ A}$	4.5	7.7	_	S
Input capacitance	)	C <sub>iss</sub>		_	1100	_	pF
Reverse transfer capacitance		C <sub>rss</sub>	$V_{DS} = -10 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	_	200	_	pF
Output capacitance		Coss		_	440	_	pF
Switching time	Rise time	t <sub>r</sub>	$V_{GS}$ $V_{DD} \simeq -50 \text{ V}$ Duty $\leq 1\%$ , $t_W = 10 \text{ μs}$		18	_	ns
	Turn-on time	t <sub>on</sub>			30	_	
	Fall time	t <sub>f</sub>		l	18	_	
	Turn-off time	t <sub>off</sub>		_	65	_	
Total gate charge (gate-source plus gate-drain)		Qg	$V_{DD} \simeq -80 \text{ V}, V_{GS} = -10 \text{ V},$	_	48		nC
Gate-source charge		Q <sub>gs</sub>	I <sub>D</sub> = -12 A		29		nC
Gate-drain ("miller") charge		Q <sub>gd</sub>			19		nC

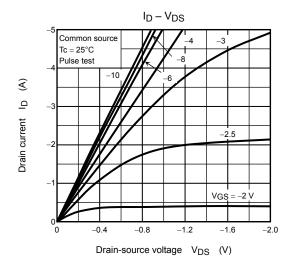
### **Source-Drain Ratings and Characteristics (Tc = 25°C)**

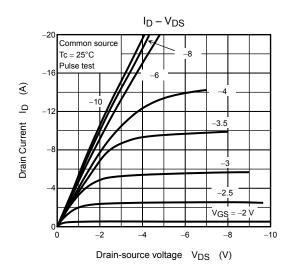
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I <sub>DR</sub>	_	_	_	-12	Α
Pulse drain reverse current (Note 1)	I <sub>DRP</sub>	_	_	_	-48	Α
Forward voltage (diode)	V <sub>DSF</sub>	$I_{DR} = -12 \text{ A}, V_{GS} = 0 \text{ V}$	_	_	1.7	V
Reverse recovery time	t <sub>rr</sub>	$I_{DR} = -12 \text{ A}, V_{GS} = 0 \text{ V}$		160	_	ns
Reverse recovery charge	Q <sub>rr</sub>	dI <sub>DR</sub> /dt = 50 A/μs	_	0.5	_	μС

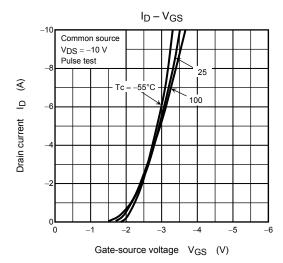
## Marking

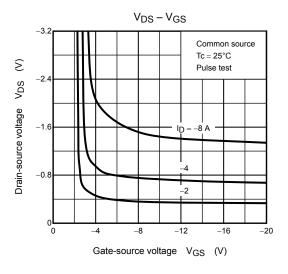


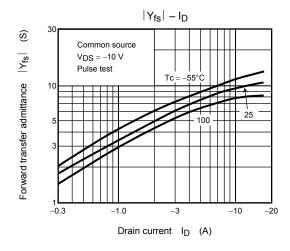
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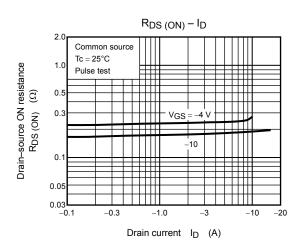


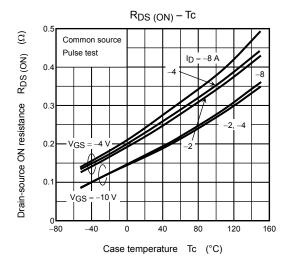


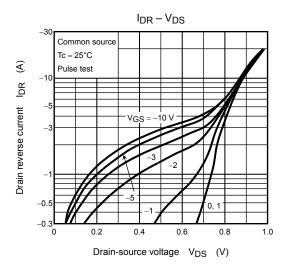


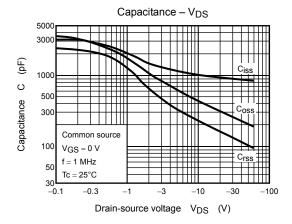


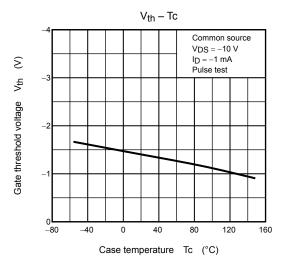


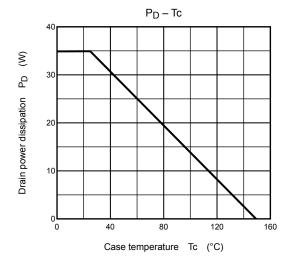


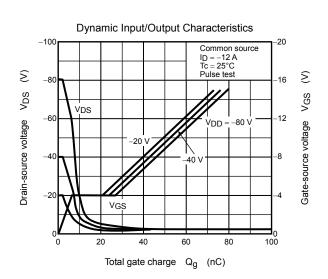


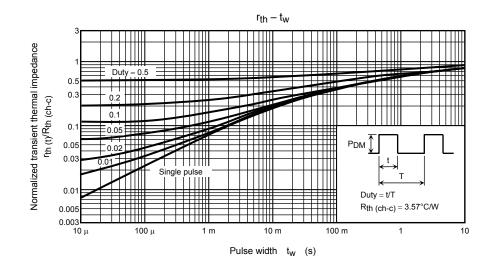


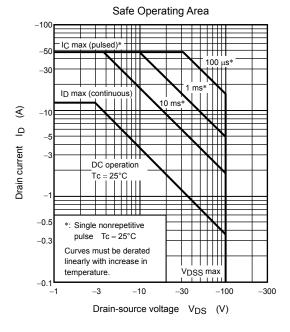


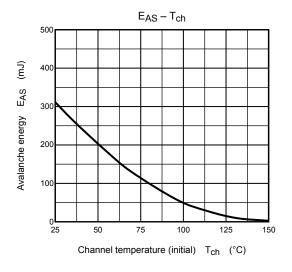


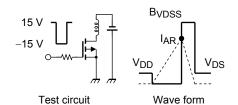












$$R_G$$
 = 25  $\Omega$   
 $V_{DD}$  = -25 V, L = 2.94 mH

$$E_{AS} = \frac{1}{2} \cdot L \cdot I^2 \cdot \left( \frac{B_{VDSS}}{B_{VDSS} - V_{DD}} \right)$$

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